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# Interfacial ferromagnetism and atomic structures in high-temperature grown $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$ epitaxial trilayers



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## ABSTRACT

Induced Pt ferromagnetism in  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  epitaxial trilayer films has been investigated by means of X-ray magnetic circular dichroism (XMCD) at the Pt  $L_{3,2}$ -edges at various temperatures from 300 K to 12 K, including the metal-insulator transition temperature of  $\text{Fe}_3\text{O}_4$  ( $T_V \sim 114$  K). At all the temperatures, we observed clear XMCD signals due to Pt ferromagnetism, the amplitude of which was determined to be  $0.39\mu_B$  at 300 K and  $0.52\mu_B$  at 12 K for the sample with the Pt thickness of  $\sim 2$  nm. Interestingly, these values are comparable to or even greater than those in Pt/3d-ferromagnetic-metal (Fe, Ni, Co, and  $\text{Ni}_{81}\text{Fe}_{19}$ ) junction systems. The results can be interpreted in terms of a possible Fe interdiffusion into the Pt layer and also possible Fe-Pt alloying due to its high-temperature deposition.

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## I. INTRODUCTION

Multilayer systems comprising paramagnetic-metal and magnetic-oxide layers have widely been used for spin-current generation and detection.<sup>1</sup> Important examples include spin Seebeck effects (SSEs)<sup>2,3</sup> and spin Hall magnetoresistance (SMR).<sup>4,5</sup> SSE refers to the generation of a spin current from a heat current in a magnetic material. The spin

current is converted into a measurable voltage via the inverse spin Hall effect (ISHE)<sup>6,7</sup> in an attached metal. SMR refers to the resistance modulation due to the simultaneous action of SHE and ISHE in a metal layer depending on the magnetization orientation in a magnetic layer. Both in SSE and SMR, Pt has often been used as a paramagnetic-metal layer due to its high SHE and ISHE efficiency,

while various garnet ferrites (e.g.,  $\text{Y}_3\text{Fe}_5\text{O}_{12}$ <sup>2–5,8</sup> and  $\text{Gd}_3\text{Fe}_5\text{O}_{12}$ <sup>9</sup>) and spinel ferrites (e.g.,  $\text{NiFe}_2\text{O}_4$ ,<sup>8,10</sup>  $\text{CoFe}_2\text{O}_4$ ,<sup>11–13</sup>  $\text{CoCr}_2\text{O}_4$ ,<sup>14</sup> and  $\text{Fe}_3\text{O}_4$ <sup>8,15–21</sup>) have been used as a magnetic layer.

In parallel with SMR or SSE, magnetic proximity effects in Pt/magnetic-oxide systems have also been studied extensively. This is because, if the proximity-induced Pt ferromagnetism exists in these systems, the ISHE voltage induced by the spin-current phenomena may be contaminated by the anisotropic magnetoresistance or anomalous Nernst effect due to the magnetized Pt.<sup>3,4,8,21–28</sup> Hence, the separation of the spin-current contribution from magnetic-proximity-effect contribution is important in spintronics, and the detection of Pt ferromagnetism in the Pt/magnetic-oxide systems has attracted much attention.<sup>29–38</sup> Recent studies demonstrated that, in Pt/ $\text{Y}_3\text{Fe}_5\text{O}_{12}$ , Pt/ $\text{NiFe}_2\text{O}_4$ , Pt/ $\text{CoFe}_2\text{O}_4$ , and Pt/ $\text{Fe}_3\text{O}_4$ , the proximity-induced parasitic contribution is negligibly small in comparison with the spin-current contribution to SMR or SSE.<sup>4,8,15,17,24–27,29,31–35,39</sup>

To investigate the proximity-induced ferromagnetism, X-ray magnetic circular dichroism (XMCD)<sup>40–42</sup> and X-ray resonant magnetic reflectivity (XRMR)<sup>43</sup> techniques have been frequently used. Since the end of the 1990s, a number of XMCD and XRMR studies focusing on Pt/3d-ferromagnetic-metal (Fe, Ni, Co, and  $\text{Ni}_{81}\text{Fe}_{19}$ ) junction systems have been reported and the Pt ferromagnetism in these systems has been established.<sup>44–56</sup> Recently, these techniques were applied for the Pt/magnetic-oxide systems: Pt/ $\text{Y}_3\text{Fe}_5\text{O}_{12}$ ,<sup>29–31,36</sup> Pt/ $\text{NiFe}_2\text{O}_4$ ,<sup>32,33,37</sup> Pt/ $\text{CoFe}_2\text{O}_4$ ,<sup>34,35,37</sup> Pt/ $\text{MnFe}_2\text{O}_4$ ,<sup>37</sup> and Pt/ $\text{Fe}_3\text{O}_4$ ,<sup>37</sup> in contrast to the Pt/3d-ferromagnetic-metal systems, the proximity-induced Pt ferromagnetism in these Pt/magnetic-oxide systems was found to be undetectably small when the effect of Pt oxidation is negligible.<sup>30,31</sup> These results suggest that small magnetization of the magnetic oxides is disadvantageous to inducing proximity ferromagnetism in the adjacent Pt layer;  $\text{Y}_3\text{Fe}_5\text{O}_{12}$ ,  $\text{NiFe}_2\text{O}_4$ ,  $\text{CoFe}_2\text{O}_4$ , and  $\text{Fe}_3\text{O}_4$  are insulators or highly-resistive conductors<sup>57–59</sup> and their volume magnetization is much smaller than that of the 3d-ferromagnetic-metals.<sup>60</sup>

In this paper, by means of XMCD at the Pt  $L_{3,2}$ -edges, we measured induced Pt ferromagnetism in  $\text{Fe}_3\text{O}_4/\text{Pt}(t_{\text{Pt}} \sim 2$  and  $5 \text{ nm})/\text{Fe}_3\text{O}_4$  epitaxial trilayer samples at various temperatures ranging from  $T = 300 \text{ K}$  to  $12 \text{ K}$ , including the metal-insulator transition temperature  $T_V$  of  $\text{Fe}_3\text{O}_4$ ; above (below)  $T_V \sim 114 \text{ K}$ ,  $\text{Fe}_3\text{O}_4$  is a resistive conductor (insulator). Thermal spin transport in Pt/ $\text{Fe}_3\text{O}_4$  epitaxial multilayers has been investigated intensively<sup>17–21,61</sup> since some of the present authors successfully fabricated the high-quality epitaxial films.<sup>17</sup> However, a possible role of the proximity-induced Pt ferromagnetism remains to be clarified.<sup>21</sup> To investigate the Pt magnetic properties via XMCD, we prepared  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  epitaxial films, where the Pt layers were sandwiched between  $\text{Fe}_3\text{O}_4$  films and deposited with high-temperature sputtering to realize the epitaxial growth, as with the previous works.<sup>17–21,61</sup> We observed a remarkably large Pt ferromagnetic moment in the  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  systems, which is comparable to or even greater than those in the conventional Pt/3d-ferromagnetic-metal junction systems. The XMCD signal monotonically increases with decreasing temperature from  $T = 300 \text{ K}$  to  $12 \text{ K}$ , across  $T_V \sim 114 \text{ K}$  of  $\text{Fe}_3\text{O}_4$ . The result is distinct from the recent XMCD study in a Pt(2 nm)/ $\text{Fe}_3\text{O}_4$  film prepared at room

temperature,<sup>37</sup> which reports the undetectably small XMCD signals at the temperatures both above and below  $T_V$ .

This paper is organized as follows. In Sec. II, we show the sample preparation procedure and the details on the experimental setup for XMCD measurements. In Sec. III A, our samples are characterized in terms of X-ray diffraction (XRD), transmission electron spectroscopy, electrical conductivity, and magnetization. From Secs. III B–III E, we show the systematic experimental results on X-ray absorption spectra (XAS) and XMCD in our samples and also discuss them. Section IV is devoted to summarizing the present study.

## II. SAMPLE PREPARATION AND EXPERIMENTAL SETUP

The  $\text{Fe}_3\text{O}_4(46 \text{ nm})/\text{Pt}(\sim 2 \text{ nm})/\text{Fe}_3\text{O}_4(54 \text{ nm})$  trilayer sample was grown on MgO (001) substrates by means of pulsed laser deposition (PLD) (for  $\text{Fe}_3\text{O}_4$ ) and sputtering (for Pt) at a high temperature of  $\sim 480^\circ\text{C}$ , which allows single-crystalline epitaxial growth.<sup>17,18,62,63</sup> All the growth processes were done *in situ* without breaking vacuum, because our PLD and sputtering systems share the same vacuum chamber. The base pressure was around  $1 \times 10^{-9}$  Torr. For the  $\text{Fe}_3\text{O}_4$  growth, polycrystalline  $\text{Fe}_3\text{O}_4$  target was ablated with a KrF excimer laser with 248 nm wavelength and 10 Hz repetition rate. The  $\text{Fe}_3\text{O}_4$  deposition was done without introducing gas at the substrate temperature of  $\sim 480^\circ\text{C}$ , which results in a chamber pressure of  $\sim 1 \times 10^{-6}$  Torr. Without any posttreatments for the  $\text{Fe}_3\text{O}_4$  and also without changing the temperature, the *in situ* Pt growth was carried out by DC magnetron sputtering with an Ar pressure of 0.5 mTorr. After forming the Pt layer, the top  $\text{Fe}_3\text{O}_4$  layer was formed by PLD under the same condition as that for the first  $\text{Fe}_3\text{O}_4$  layer on the MgO substrate. After the growth of the top  $\text{Fe}_3\text{O}_4$  layer was completed, the substrate temperature was cooled down to room temperature at the rate of  $10^\circ\text{C}/\text{min}$ . We note that in Ref. 63, some of the present authors reported the absence of other Fe phases apart from  $\text{Fe}_3\text{O}_4$  in the  $\text{Fe}_3\text{O}_4$  films, fabricated by the same procedure, by means of X-ray photoemission spectroscopy (XPS) on Fe 2p core level in  $\text{Fe}_3\text{O}_4$  films, where the electronic state only in the near-surface region ( $\leq 1 \text{ nm}$  from the surface<sup>64</sup>) is detected. To check the effect of Pt thickness on XMCD, we also fabricated a similar  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  sample with the Pt thickness of  $t_{\text{Pt}} \sim 5 \text{ nm}$  under the same condition. Besides, a Pt( $\sim 5 \text{ nm}$ )/ $\text{Fe}_3\text{O}_4(40 \text{ nm})/\text{Pt}(\sim 2 - 3 \text{ nm})/\text{Fe}_3\text{O}_4(47 \text{ nm})$  sample was prepared to investigate possible Fe contamination in the (top) Pt film formed on  $\text{Fe}_3\text{O}_4$  via X-ray absorption spectra (XAS) and XMCD measurements at the Fe  $L_{3,2}$ -edges.

The XMCD experiments at the Pt  $L_{3(2)}$ -edge [ $2p_{3/2(1/2)} \rightarrow 5d$  transition] were performed at the beamline BL39XU of SPring-8 synchrotron radiation facility using the fluorescence detection mode.<sup>48</sup> XAS were recorded with circularly-polarized X-rays while reversing their helicity at 1 Hz. The circularly-polarized X-rays with a high degree of polarization ( $\geq 95\%$ ) were generated by using a diamond X-ray phase retarder. The Pt  $L_{\alpha(\beta)}$  [for the Pt  $L_{3(2)}$ -edge] fluorescence were measured with a silicon drift detector. During the XMCD measurements, the  $\text{Fe}_3\text{O}_4/\text{Pt}(t_{\text{Pt}} \sim 2$  and  $5 \text{ nm})/\text{Fe}_3\text{O}_4/\text{MgO}$  sample was placed in an electromagnet, where an external magnetic field,  $H$ , was applied to the sample at the angle of  $5^\circ$  with respect to the sample surface. Here, the  $H$  direction was parallel or antiparallel

to the direction of the angular momentum vector of the incident X-ray beam. The measurements of element-specific magnetization (ESM) curves were also carried out at the constant energy of  $E = 11\,569\text{ eV}$  (the XMCD peak position for the Pt  $L_3$ -edge) in the range of  $|H| \leq 20\text{ kOe}$  at  $T = 300\text{ K}$  and  $|H| \leq 12\text{ kOe}$  at  $T = 12\text{ K}$ .

### III. RESULTS AND DISCUSSION

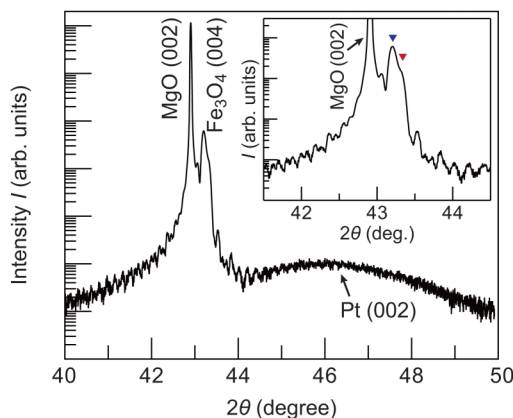
#### A. Sample characterization

##### 1. X-ray diffraction

Figure 1 shows the X-ray diffraction (XRD) patterns of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4/\text{MgO}$  sample around the (002) Bragg peak from the MgO substrate. We observed the (004) reflection from the  $\text{Fe}_3\text{O}_4$  layers as well as the (002) reflection from the Pt layer, which confirms the out-of-plane orientation of  $\text{Fe}_3\text{O}_4[001]/\text{Pt}[001]/\text{Fe}_3\text{O}_4[001]/\text{MgO}[001]$ . As shown in the inset to Fig. 1, the (004) reflection of  $\text{Fe}_3\text{O}_4$  consists of two peaks with slightly different peak angles,  $43.20^\circ$  and  $43.30^\circ$ , marked with blue and red triangles, respectively. This result is due to the different underlayers for each  $\text{Fe}_3\text{O}_4$  layer; the peak at the lower (higher) angle can be attributed to the diffraction from the  $\text{Fe}_3\text{O}_4$  layer grown on the MgO substrate (grown on the Pt film), since the peak position at the lower one is in agreement with that of the (004) reflection from a  $\text{Fe}_3\text{O}_4$  film grown on a MgO (001) substrate.<sup>17</sup> From the positions of the diffraction peaks, the out-of-plane lattice constants for the  $\text{Fe}_3\text{O}_4$  layers grown on the MgO substrate and grown on the Pt film were, respectively, determined to be  $8.370\text{ \AA}$  and  $8.352\text{ \AA}$ . The Laue oscillations of the (004) reflection were observed for both the  $\text{Fe}_3\text{O}_4$  layers, indicating high crystalline coherence of each  $\text{Fe}_3\text{O}_4$  layer.

##### 2. Transmission electron microscopy

To further investigate the structural quality of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample, we performed transmission



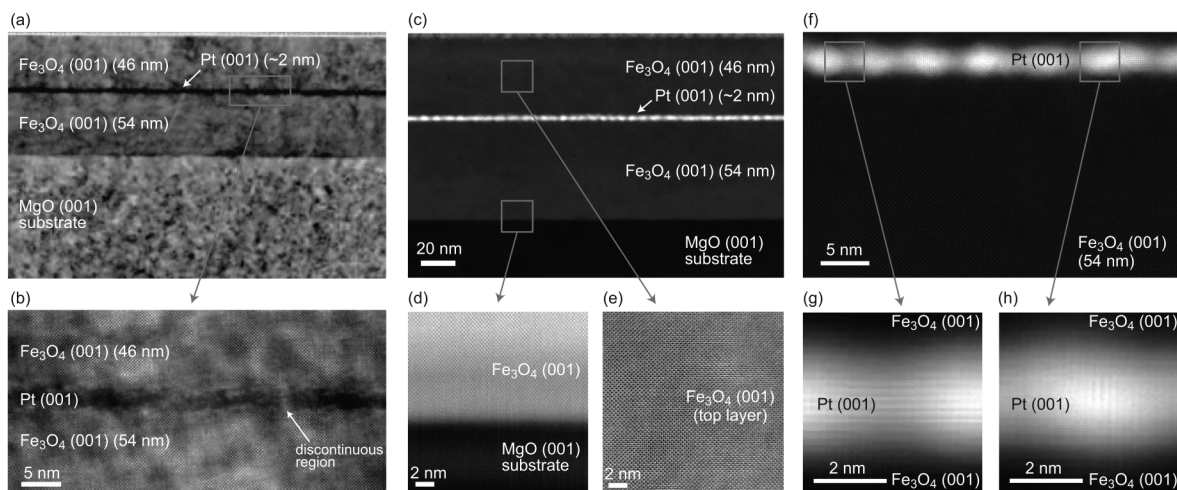
**FIG. 1.**  $2\theta$ - $\omega$  diffraction patterns of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  trilayer sample grown on the MgO (001) substrate. The inset shows the magnified view in the range of  $41.50^\circ < 2\theta < 44.50^\circ$ , where the  $\text{Fe}_3\text{O}_4$  (004) diffraction peaks at lower and higher angles are marked by the blue and red triangles, respectively.

electron microscopy (TEM) and high-angle annular dark-field scanning TEM (HAADF-STEM) (see Fig. 2). The images of the overall sample cross section [Figs. 2(a) and 2(c)] show that each layer has a smooth surface and mostly uniform thickness. We confirmed that the bottom (first)  $\text{Fe}_3\text{O}_4$  layer is epitaxially grown on the MgO (001) substrate and its interface is sharp [see Fig. 2(d) and its clear contrast change at the  $\text{Fe}_3\text{O}_4/\text{MgO}$  interface]. The Pt layer formed on the first  $\text{Fe}_3\text{O}_4$  layer also shows epitaxial growth with the [001] orientation [see Figs. 2(g) and 2(h)]. Subsequently, the top (second)  $\text{Fe}_3\text{O}_4$  layer is also found to grow epitaxially on the Pt (001) layer with keeping high crystallization. These results ensure full epitaxial growth from the substrate to the top  $\text{Fe}_3\text{O}_4$  layer, consistent with the XRD result.

From the high resolution (HR) HAADF-STEM images shown in Figs. 2(g) and 2(h), we notice that there exists intermediate brightness regions and soft undulation between the Pt and  $\text{Fe}_3\text{O}_4$  interface, indicating that the Pt film may be discontinuous and/or that the Pt/ $\text{Fe}_3\text{O}_4$  interface may not be atomically sharp. In fact, the HR-TEM image in Fig. 2(b) captures a discontinuous region of Pt, and also the STEM images in Figs. 2(c) and 2(f) indicate that the Pt film consists of clusterlike structures due to the granular-type growth of Pt. To clarify the origin of the intermediate brightness regions and soft undulation at the Pt/ $\text{Fe}_3\text{O}_4$  interface in more detail, we fabricated a  $\text{Fe}_3\text{O}_4/\text{Pt}(10\text{ nm})/\text{Fe}_3\text{O}_4$  sample; owing to the Pt film much thicker than the previous sample, we can examine the interfacial property without considering the effect of discontinuity of the Pt film. Figure 3(a) shows the HR-TEM bright field image of the interface between the 10-nm-thick Pt and  $\text{Fe}_3\text{O}_4$  formed on a MgO substrate. We found that in the vicinity of the Pt/ $\text{Fe}_3\text{O}_4$  interface, there are small lobules (nanograins) ( $< 1\text{ nm}$ ) consisting of  $\text{Fe}_3\text{O}_4$  and Pt that are alternately formed with each other along the lateral direction [see Fig. 3(a)]. Figure 3(b) shows a corresponding HR-HAADF-STEM image of the same sample. The alternate  $\text{Fe}_3\text{O}_4$  and Pt lobules observed by HR-TEM [Fig. 3(a)] were found to appear as intermediate brightness and soft undulation in the region around 1.5–2 unit cells of the Pt film from the interface. To evaluate the interfacial Fe, O, and Pt elements profile, we carried out electron energy loss spectroscopy (EELS) and energy dispersive X-ray spectroscopy (EDX).<sup>21</sup> As shown in Fig. 3(c), around the interface, the element profile varies in the range of 0.75–1 nm and there are finite Fe and O contributions in the Pt layer. This can be due to the overlap of the interfacial  $\text{Fe}_3\text{O}_4$  and Pt lobules [Fig. 3(a)] existing along the depth direction (i.e., perpendicular to the cross plane) or simply due to some Pt, Fe, and O diffusion. Unfortunately, we cannot separate these two possible contributions in the present analysis.

##### 3. Electric and magnetic properties of $\text{Fe}_3\text{O}_4$

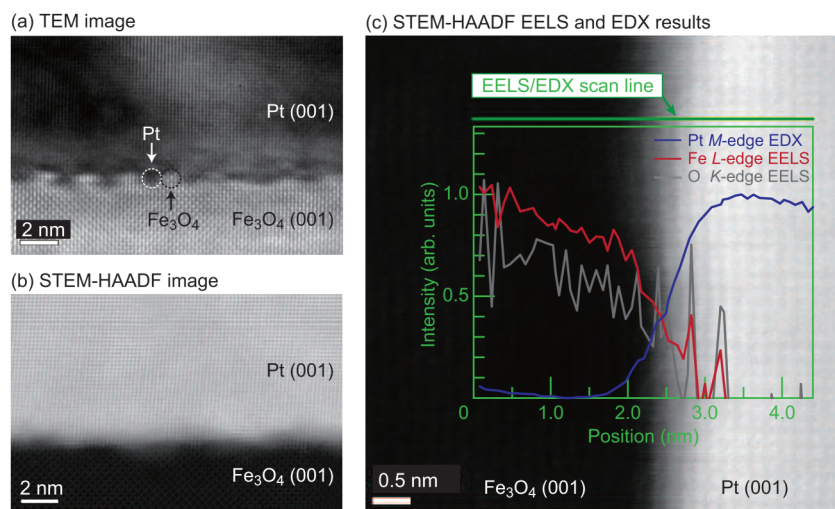
We also characterized the electric and magnetic properties of the  $\text{Fe}_3\text{O}_4$  film by four-probe conductivity measurements and vibrating sample magnetometry, respectively. We found that the electrical conductivity  $\sigma$  of our  $\text{Fe}_3\text{O}_4$  film is  $\sim 1.4 \times 10^2/\Omega\text{ cm}$ , being consistent with the literature value,<sup>65</sup> which confirms the metallic behavior of the  $\text{Fe}_3\text{O}_4$  film at room temperature. As shown in Fig. 4(a), as the temperature  $T$  decreases,  $\sigma$  was found to monotonically decrease. Moreover, below  $\sim 110\text{ K}$ ,  $\sigma$  dramatically



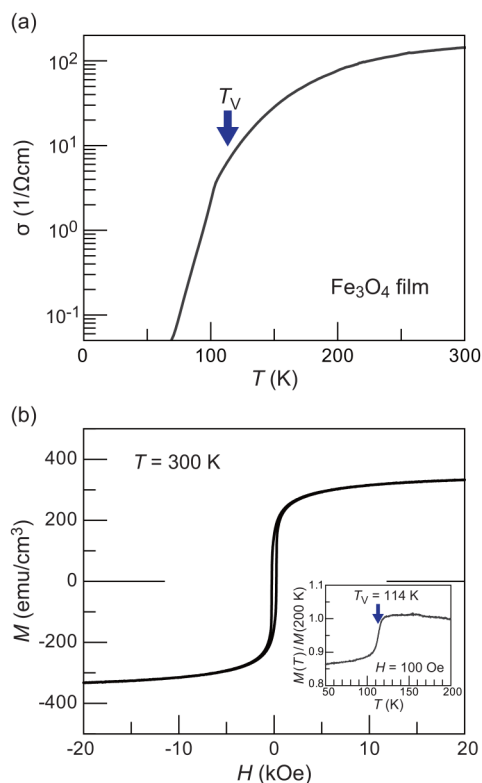
**FIG. 2.** (a) and (b) Cross-sectional TEM images of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4//\text{MgO}$  sample for (a) the overall sample cross section and for (b) the  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  interfaces with higher resolution. (c)–(h) HAADF-STEM images of the  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4//\text{MgO}$  sample for (c) the overall sample cross section, for (d) the  $\text{Fe}_3\text{O}_4/\text{MgO}$  interface, for (e) the top  $\text{Fe}_3\text{O}_4$  layer grown on the Pt layer, and for (f) the  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  interfaces. The HR-HAADF-STEM images focusing on the vicinity of the  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  interfaces are shown in (g) and (h). The TEM lamellae specimen was prepared using a focused ion beam. HAADF-STEM was carried out with a probe-aberration-corrected FEI Titan 60-300 operated at 300 kV.

decreases with decreasing  $T$ , showing the metal-insulator (Verwey) transition of  $\text{Fe}_3\text{O}_4$ .<sup>40,65</sup> Figure 4(b) shows the observed magnetic field  $H$  dependence of the magnetization  $M$  ( $M$ - $H$  curve) for the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample at  $T = 300\text{ K}$ . The saturation  $M$  value was found to be  $333\text{ emu/cm}^3$ , smaller than the bulk value of

$480\text{ emu/cm}^3$ ,<sup>60</sup> which can be attributed to the higher density of antiphase boundaries of PLD-grown  $\text{Fe}_3\text{O}_4$  films.<sup>63,66</sup> From  $M$ - $T$  curves, the Verwey transition temperature ( $T_V$ ) of our  $\text{Fe}_3\text{O}_4$  films was determined to be  $\sim 114\text{ K}$  [see the inset in Fig. 4(b)], consistent with the literature values for  $\text{Fe}_3\text{O}_4$  films with similar thickness.<sup>63</sup>



**FIG. 3.** (a) HR-TEM and (b) HR-HAADF-STEM images around the  $\text{Pt}/\text{Fe}_3\text{O}_4$  interface of the  $\text{Fe}_3\text{O}_4/\text{Pt}(10\text{ nm})/\text{Fe}_3\text{O}_4//\text{MgO}$  sample. In (a), the observed small  $\text{Fe}_3\text{O}_4$  and Pt lobules (nanograins) are marked by dashed circles. (c) EDX line scan for Pt ( $M$ -edge, blue solid line) and EELS line scans for Fe ( $L$ -edge, red solid line) and O ( $K$ -edge, gray solid line) across the interface indicated by the green solid line.<sup>21</sup> The EELS measurement was done by using a probe-corrected Titan G2, where the beam diameter is around  $0.1 - 0.15\text{ nm}$ , ensuring enough resolution to probe the elements at the interface. Besides, by diffraction analysis, the incident electron beam was directed to be orthogonal to the film cross plane. This ensures that the observed signal comes from the parallel plane and does not come from crosswise planes that may result in an artificial composition-mixed signal.

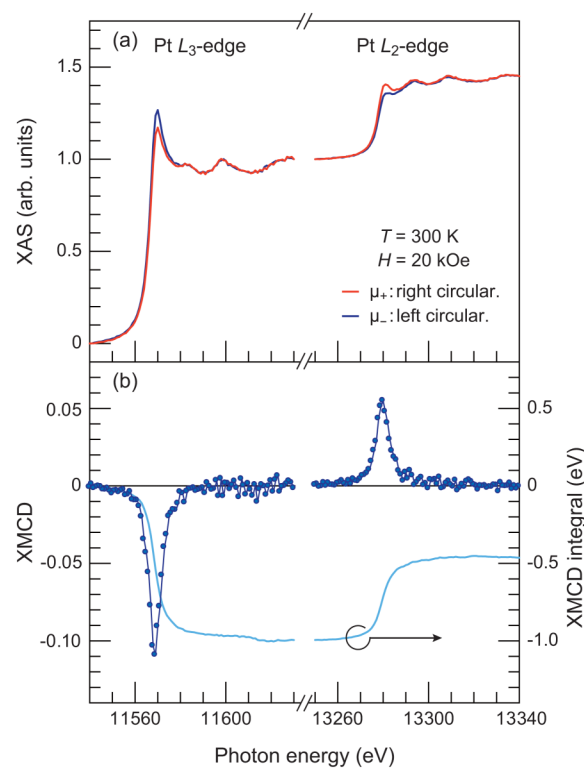


**FIG. 4.** (a)  $T$  dependence of the electrical conductivity  $\sigma$  for a 40-nm-thick  $\text{Fe}_3\text{O}_4$  (001) film grown on a  $\text{MgO}$  (001) substrate. (b)  $M$ - $H$  curve of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample at  $T = 300\text{ K}$ , measured with a vibrating sample magnetometer. The inset to (b) shows the normalized  $M$ - $T$  curve measured at  $H = 100\text{ Oe}$ . The external field of 100 Oe is smaller than the coercive field of  $\text{Fe}_3\text{O}_4$  ( $H_c \sim 250\text{ Oe}$ ). The  $T_V$  value can be determined via this measurement, since, with decreasing  $T$ , the  $M$  value at  $H < H_c$  steeply decreases when the Verwey transition occurs at  $T = T_V$  due to the enhancement of  $H_c$  (magnetic anisotropy).<sup>65,66</sup>

## B. XAS, XMCD, and ESM results at $T = 300\text{ K}$

Now, we present the results on the X-ray absorption of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample at  $T = 300\text{ K}$  and  $H = 20\text{ kOe}$ . Figure 5(a) shows the measured XAS for the Pt  $L_{3,2}$ -edges with right ( $\mu_+$ ) and left ( $\mu_-$ ) circularly-polarized X-rays, where the XAS edge jump is normalized to 1 ( $2.22^{-1}$ ) for the  $L_3$ -edge ( $L_2$ -edge).<sup>67,68</sup> The whiteline intensity, the ratio of the absorption maximum at the  $L_3$ -edge to the edge jump, of  $(\mu_+ + \mu_-)/2$  is estimated to be  $\sim 1.25$ , comparable to that for a Pt foil.<sup>31,68</sup> Oscillation behaviors were observed in the extended X-ray absorption fine structure (EXAFS) region. These are characteristics of metallic Pt,<sup>31</sup> ensuring the quality of our Pt film.

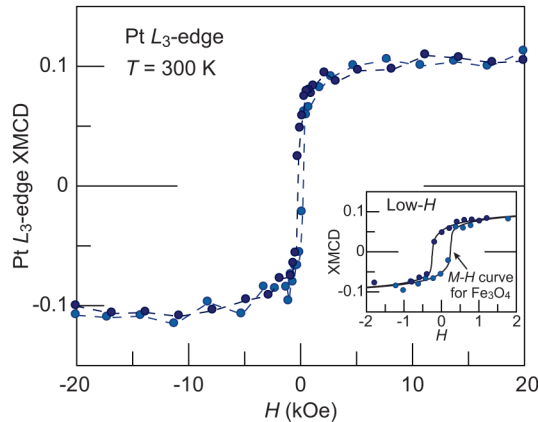
The XAS shown in Fig. 5(a) exhibits a clear helicity dependence. Figure 5(b) shows the corresponding XMCD spectra ( $\mu_+ - \mu_-$ ) at  $T = 300\text{ K}$  and  $H = 20\text{ kOe}$ . The sign of the XMCD signal is negative at the  $L_3$ -edge (11 569 eV) and positive at the  $L_2$ -edge (13 280 eV), consistent with Pt films having magnetic



**FIG. 5.** (a) The normalized XAS for the Pt  $L_{3,2}$ -edges of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample at  $T = 300\text{ K}$  and  $H = 20\text{ kOe}$ . The XAS edge jump, defined as the difference in the XAS intensity between 11 540 eV (13 250 eV) and 11 630 eV (13 340 eV), is normalized to 1 ( $2.22^{-1}$ ) for the  $L_3$ -edge ( $L_2$ -edge) according to Refs. 67 and 68. The XAS offset value for the  $L_3$ -edge ( $L_2$ -edge) is set to be 0 (1).<sup>29,31,51,68</sup>  $\mu_+$  ( $\mu_-$ ) represents the XAS obtained with the right (left) circularly-polarized X-rays. (b) The XMCD spectra (blue circles with solid lines) and their integral (light-blue solid lines) for the Pt  $L_{3,2}$ -edges of the  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  sample.

moments parallel to  $H$ .<sup>48,51</sup> Significantly, the XMCD intensity of  $\sim 0.11$  (0.055) at the  $L_3$ -edge ( $L_2$ -edge) with respect to the XAS edge jump is two orders of magnitude greater than that for a Pt foil,<sup>58</sup> in which only the Pauli paramagnetism of Pt appears. This result suggests that our Pt film sandwiched between the  $\text{Fe}_3\text{O}_4$  films acquires considerable induced magnetic moments, a situation different from the previous reports in conventional Pt/magnetic-oxide systems<sup>29,31–35</sup> including the  $\text{Pt}(2\text{ nm})/\text{Fe}_3\text{O}_4$  system reported in Ref. 37.

To check the  $H$  dependence of the induced moments in Pt, we measured the ESM curve at the Pt  $L_3$ -edge. We found that the XMCD magnitude increases with increasing  $H$  from zero and saturates at  $H \sim 5\text{ kOe}$  and that the sign of the XMCD signal changes by reversing the  $H$  direction (see Fig. 6). The ESM curve is well consistent with the ferromagnetic  $M$ - $H$  curve for the  $\text{Fe}_3\text{O}_4$  layers (see the inset to Fig. 6), suggesting that the observed XMCD signal is due to the Pt ferromagnetism whose magnetization process is governed by the  $\text{Fe}_3\text{O}_4$  layers.



**FIG. 6.** The ESM curve at the Pt  $L_{3}$ -edge of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample at  $T = 300\text{ K}$  and the fixed photon energy of  $11\,569\text{ eV}$ . The inset shows the comparison between the ESM curve (dark-blue and blue circles) and the  $M$ - $H$  curve for the  $\text{Fe}_3\text{O}_4$  layers (black solid lines, in arbitrary units) in the range of  $|H| < 2\text{ kOe}$ .

The observed XMCD intensity, or the induced magnetic moment, in the present  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  sample is quite large. The Pt ferromagnetic moment value at  $H = 20\text{ kOe}$  was estimated to be  $m_{\text{tot}} = m_{\text{orb}} + m_{\text{spin}} = 0.39 \pm 0.05\mu_{\text{B}}$  by XMCD

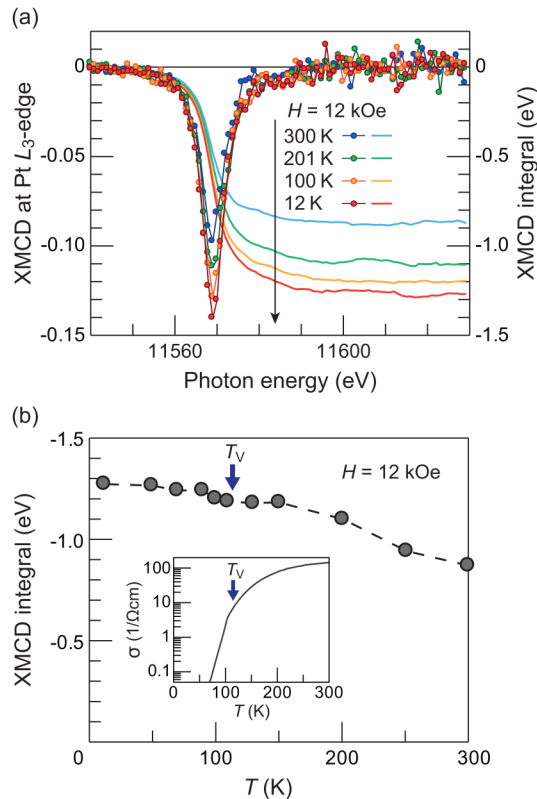
sum-rule analysis,<sup>48,69,70</sup> where  $m_{\text{orb}} = 0.05 \pm 0.01\mu_{\text{B}}$  and  $m_{\text{spin}} = 0.34 \pm 0.05\mu_{\text{B}}$  are the orbital and (effective) spin magnetic moments, respectively (see Sec. A in the [supplementary material](#) for details on the sum-rule analysis). The ratio of the orbital-to-spin magnetic moment is  $m_{\text{orb}}/m_{\text{spin}} = 0.15 \pm 0.02$ . Interestingly, the  $m_{\text{tot}}$  value is comparable to or greater than those in Pt/ $3d$ -ferromagnetic-metal (Fe, Ni, Co, and  $\text{Ni}_{81}\text{Fe}_{19}$ ) junction and  $L_{10}$ -FePt alloy systems (see [Table I](#)). For example, the  $m_{\text{tot}}$  values in the Pt(2 and 1 nm)/Co bilayers were, respectively, reported to be  $0.16\mu_{\text{B}}$  and  $0.28\mu_{\text{B}}$ ,<sup>48</sup> which are smaller than that in our  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  trilayer system. Also, the  $m_{\text{tot}}$  value in the Pt(1 nm)/ $\text{Ni}_{81}\text{Fe}_{19}$  superlattice (SL) system, where the Pt film is sandwiched by ferromagnetic  $\text{Ni}_{81}\text{Fe}_{19}$  layers in a similar way as our sample system, was estimated to be  $0.27\mu_{\text{B}}$ ,<sup>53</sup> again giving a value smaller than the present one. In contrast, the  $m_{\text{orb}}/m_{\text{spin}}$  ratio is almost the same as those in the previous Pt/ $3d$ -ferromagnetic-metal junctions (see [Table I](#)).

### C. Temperature dependence of XMCD

We carried out systematic measurements on the  $T$  dependence of the XMCD using the same  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample. [Figure 7\(a\)](#) shows the Pt  $L_{3}$ -edge XMCD spectra at  $H = 12\text{ kOe}$  at several  $T$  values (left vertical axis) and their integrals (right vertical axis) and [Fig. 7\(b\)](#) shows the XMCD-integral values as a function of  $T$ . We found that the XMCD amplitude monotonically increases with decreasing  $T$  [see [Fig. 7\(a\)](#)]. The XMCD-integral value at the

**TABLE I.** Comparison of induced Pt magnetic moments at room temperature in various junction systems comprising Pt and magnetic materials and also  $L_{10}$ -FePt alloys.<sup>71</sup>  $M_{\text{FM}}$  represents the volume magnetization value of the ferro(ferri)magnetic (FM) layers. The  $M_{\text{FM}}$  value for  $L_{10}$ -FePt alloys is obtained by calculating the Fe contribution to the volume magnetization of  $L_{10}$ -FePt.

| System  | Method | $m_{\text{tot}}$<br>( $\mu_{\text{B}}/\text{Pt}$ ) | $m_{\text{spin}}$<br>( $\mu_{\text{B}}/\text{Pt}$ ) | $m_{\text{orb}}$<br>( $\mu_{\text{B}}/\text{Pt}$ ) | $m_{\text{orb}}/m_{\text{spin}}$ | $M_{\text{FM}}$<br>( $\text{emu}/\text{cm}^3$ ) | Comment on<br>Pt fabrication |
|---|--------|--|---|--|----------------------------------|---|------------------------------|
| $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$ | XMCD   | 0.39   | 0.34  | 0.050  | 0.15                             | 333   | High- $T$ growth             |
| $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 5\text{ nm})/\text{Fe}_3\text{O}_4$ | XMCD   | 0.36   | 0.32  | 0.043  | 0.14                             | 333   | High- $T$ growth             |
| Pt(2 nm)/Co <sup>48</sup>   | XMCD   | 0.16   | 0.14  | 0.020  | 0.14                             | 1440 <sup>60</sup>                              |                              |
| Pt(1 nm)/Co <sup>48</sup>   | XMCD   | 0.28   | 0.24  | 0.037  | 0.15                             | 1440 <sup>60</sup>                              |                              |
| Pt/Fe interface <sup>32</sup>   | XRMR   | 0.6  |   |  |                                  | 1710 <sup>60</sup>                              |                              |
| Pt/ $\text{Ni}_{81}\text{Fe}_{19}$ interface <sup>52</sup>                | XRMR   | 0.22   |   |  |                                  | 830 <sup>60</sup>                               |                              |
| Pt/Ni interface <sup>52</sup>   | XRMR   | 0.08   |   |  |                                  | 488 <sup>60</sup>                               |                              |
| Pt(1 nm)/ $\text{Ni}_{81}\text{Fe}_{19}$ SL <sup>53</sup>                 | XMCD   | 0.27   |   |  | 0.18                             | 830 <sup>60</sup>                               |                              |
| $L_{10}$ -FePt alloy <sup>55</sup>  | XMCD   | 0.38   | 0.30  | 0.075  | 0.25                             | 840 <sup>55</sup>                               |                              |
| $L_{10}$ -FePt alloy <sup>56</sup>  | XMCD   | 0.32   | 0.28  | 0.039  | 0.14                             | 840 <sup>56</sup>                               |                              |
| Pt(1.5 nm)/ $\text{Y}_3\text{Fe}_5\text{O}_{12}$ <sup>30</sup>            | XMCD   | 0.054  | 0.044   | 0.010  | 0.23                             | 140 <sup>30</sup>                               |                              |
| Pt(3 nm)/ $\text{Y}_3\text{Fe}_5\text{O}_{12}$ <sup>29</sup>              | XMCD   | <0.003   |   |  |                                  | 110 <sup>29</sup>                               |                              |
| Pt(2 nm)/ $\text{Fe}_3\text{O}_4$ <sup>37</sup>                           | XMCD   | <0.005   |   |  |                                  | $\sim 500$ <sup>37</sup>                        | Room- $T$ growth             |
| Pt(7 nm)/ $\text{CoFe}_2\text{O}_4$ <sup>35</sup>                         | XMCD   | <0.002   |   |  |                                  | 160 <sup>35</sup>                               |                              |
| Pt(2 nm)/ $\text{CoFe}_2\text{O}_4$ <sup>37</sup>                         | XMCD   | <0.005   |   |  |                                  | $\sim 200$ <sup>37</sup>                        | Room- $T$ growth             |
| Pt(4 nm)/ $\text{CoFe}_2\text{O}_4$ <sup>38</sup>                         | XMCD   | <0.01  |   |  |                                  | $\sim 340$ <sup>38</sup>                        | Room- $T$ growth             |
| Pt(4 nm)/ $\text{CoFe}_2\text{O}_4$ <sup>38</sup>                         | XMCD   | 0.24   |   |  |                                  | $\sim 340$ <sup>38</sup>                        | High- $T$ growth             |
| Pt(2 nm)/ $\text{MnFe}_2\text{O}_4$ <sup>37</sup>                         | XMCD   | <0.005   |   |  |                                  | $\sim 100$ <sup>37</sup>                        | Room- $T$ growth             |
| Pt(2 nm)/ $\text{NiFe}_2\text{O}_4$ <sup>37</sup>                         | XMCD   | <0.005   |   |  |                                  | $\sim 70$ <sup>37</sup>                         | Room- $T$ growth             |
| Pt/ $\text{NiFe}_2\text{O}_4$ interface <sup>32</sup>                     | XRMR   | <0.02  |   |  |                                  | $\sim 230$ <sup>32</sup>                        |                              |
| Pt/ $\text{NiFe}_2\text{O}_4$ interface <sup>33</sup>                     | XRMR   | <0.04  |   |  |                                  | 244 <sup>33</sup>                               |                              |

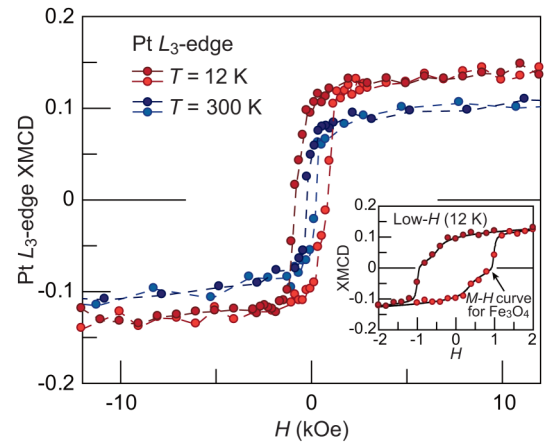


**FIG. 7.** (a) The XMCD spectra for the Pt  $L_{3}$ -edge of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample (left vertical axis) and their integral (right vertical axis) measured at  $H = 12\text{ kOe}$  at several  $T$  values. (b)  $T$  dependence of the XMCD integral at  $H = 12\text{ kOe}$ . The inset to (b) shows the  $T$  dependence of  $\sigma$  of the  $\text{Fe}_3\text{O}_4$  film, which is the same as that shown in Fig. 4(a).

lowest temperature (12 K) increases by a factor of  $\sim 1.4$  compared to that at 300 K. Interestingly, this enhancement is more prominent than that of magnetization of  $\text{Fe}_3\text{O}_4$  ( $\sim 1.05$  in the same  $T$  range<sup>73</sup>). Furthermore, the metal-insulator transition of  $\text{Fe}_3\text{O}_4$  does not affect the present Pt ferromagnetism, since no meaningful change of the XMCD signal was observed at around  $T_V \sim 114\text{ K}$  [see Fig. 7(b)].

Figure 8 shows the ESM curve at the Pt  $L_{3}$ -edge at 12 K (dark-red and red circles) and the comparison of the ESM curve with that at 300 K (dark-blue and blue circles). We found that the amplitude of the ESM curve at 12 K is greater than that at 300 K, consistent with the XMCD spectra shown in Fig. 7(a). We also found that the coercivity of the ESM curve enhances at 12 K compared to that at 300 K, in agreement with that of the  $M$ - $H$  curve of the  $\text{Fe}_3\text{O}_4$  layers (see the inset of Fig. 8), which is due to the increase of the magnetic anisotropy of  $\text{Fe}_3\text{O}_4$  below  $T_V$ .<sup>66</sup>

From the integrated XAS and XMCD measured at  $T = 12\text{ K}$  and  $H = 12\text{ kOe}$ , the Pt ferromagnetic moment value under this condition was estimated to be  $m_{\text{tot}} = m_{\text{orb}} + m_{\text{spin}} = 0.52 \pm 0.06\mu_B$ ,



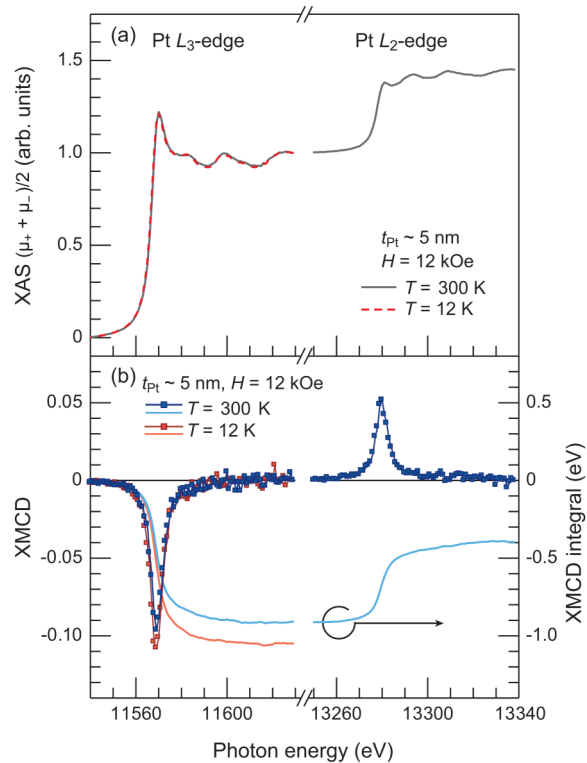
**FIG. 8.** The ESM curve at the Pt  $L_{3}$ -edge of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2\text{ nm})/\text{Fe}_3\text{O}_4$  sample at  $T = 12\text{ K}$  (dark-red and red circles with dashed lines). For comparison, the ESM curve measured at  $T = 300\text{ K}$  is also plotted (dark-blue and blue circles with dashed lines). The inset shows the comparison between the ESM curve at  $T = 12\text{ K}$  (dark-red and red circles) and  $M$ - $H$  curve for the  $\text{Fe}_3\text{O}_4$  layers at  $T = 10\text{ K}$  (black solid lines, in arbitrary units) in the range of  $|H| < 2\text{ kOe}$ .

where  $m_{\text{orb}} = 0.06 \pm 0.01\mu_B$  and  $m_{\text{spin}} = 0.46 \pm 0.06\mu_B$  (see Sec. B in the supplementary material for details, in which the XAS and XMCD full spectra for the Pt  $L_{3,2}$ -edges at 12 K and 12 kOe are shown). As expected from the XMCD data shown in Fig. 7(b), the  $m_{\text{tot}}$  value at 12 K increases by a factor of  $\sim 1.4$  compared to that at 300 K. On the other hand, the ratio of the orbital-to-spin magnetic moment is  $m_{\text{orb}}/m_{\text{spin}} = 0.13 \pm 0.01$ , which agrees with that estimated at 300 K within the experimental error. The  $m_{\text{tot}}$  value at 12 K is more than two times greater than that in Pt/Ni junction systems at similar temperatures<sup>44–46</sup> and is comparable to (or even slightly greater than) that of  $L1_0$ -FePt alloys ( $= 0.45 \pm 0.03\mu_B/\text{Pt}$  at 15 K<sup>54</sup>).

#### D. Effect of Pt thickness on XMCD

To reveal the effect of Pt thickness  $t_{\text{Pt}}$  on the XMCD amplitude, we also measured XMCD using a  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 5\text{ nm})/\text{Fe}_3\text{O}_4$  sample at  $T = 300\text{ K}$  and 12 K, where the 2-nm-thick Pt film is replaced with the thicker one ( $t_{\text{Pt}} \sim 5\text{ nm}$ ). As shown in Fig. 9(a), clear XMCD signals were observed, whose intensity at 12 K is larger than that at 300 K, consistent with the  $t_{\text{Pt}} \sim 2\text{ nm}$  sample. From the integrated XAS and XMCD measured at  $T = 300\text{ K}$ , the Pt ferromagnetic moment value of the present  $t_{\text{Pt}} \sim 5\text{ nm}$  sample was estimated to be  $m_{\text{tot}} = m_{\text{orb}} + m_{\text{spin}} = 0.36 \pm 0.04\mu_B$ , where  $m_{\text{orb}} = 0.043 \pm 0.007\mu_B$  and  $m_{\text{spin}} = 0.32 \pm 0.04\mu_B$ . These values are comparable to those for the  $t_{\text{Pt}} \sim 2\text{ nm}$  sample at  $T = 300\text{ K}$  within the experimental error (see also Table I). The Pt thickness dependence result is distinct from the previous XMCD study at the Pt  $L_{3,2}$ -edges of  $\text{Pt}(t_{\text{Pt}})/\text{Co}$  samples,<sup>48</sup> where the substantial decrease of the XMCD signal with increasing  $t_{\text{Pt}}$  is observed. In Ref. 48, this feature is explained by the model that the





**FIG. 9.** (a) The normalized XAS  $[(\mu_+ + \mu_-)/2]$  for the Pt  $L_{3,2}$ -edges of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 5 \text{ nm})/\text{Fe}_3\text{O}_4$  sample at  $T = 300 \text{ K}$  and  $H = 12 \text{ kOe}$  (gray solid lines). (b) The XMCD spectra (blue circles with solid lines) and the corresponding XMCD integrals (light-blue solid lines) at  $T = 300 \text{ K}$  and  $H = 12 \text{ kOe}$  for the Pt  $L_{3,2}$ -edges of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 5 \text{ nm})/\text{Fe}_3\text{O}_4$  sample. In (a) and (b), the normalized XAS and the XMCD spectrum/integral for the Pt  $L_{3,2}$ -edge of the  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 5 \text{ nm})/\text{Fe}_3\text{O}_4$  sample measured at  $T = 12 \text{ K}$  are also plotted, respectively.

ferromagnetic Pt moment exponentially decreases with the distance from the interface, the decay length of which is estimated to be 0.41 nm.

### E. Discussion on the large Pt ferromagnetic moment in $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$

The giant Pt ferromagnetic moment  $m_{\text{tot}}$  value in the present  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  systems is unconventional in the light of the volume magnetization ( $M_{\text{FM}}$ ) value of the  $\text{Fe}_3\text{O}_4$  layers. In the previous reports for the Pt/ $3d$ -ferromagnetic-metal junction systems at room temperature, the proximity-induced  $m_{\text{tot}}$  values tend to scale with the  $M_{\text{FM}}$  values of the ferromagnetic layers (see Table I for 300 K). In fact, the  $m_{\text{tot}}$  vs  $M_{\text{FM}}$  scaling was recently confirmed for Pt/ $\text{Ni}_{1-x}\text{Fe}_x$  and Pt/ $\text{Co}_{1-x}\text{Fe}_x$  bilayers via XRMR measurements in Ref. 73. However, our XMCD result clearly deviates from this tendency; although the  $M_{\text{FM}}$  value of the  $\text{Fe}_3\text{O}_4$  layer is much smaller than those of the  $3d$ -ferromagnetic-metal layers as shown in Table I, the  $m_{\text{tot}}$  value in our systems is comparable to or greater

than those in the Pt/ $3d$ -ferromagnetic-metal systems. Such deviation may become more outstanding at the lowest temperature (12 K); the  $m_{\text{tot}}$  value in the present  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2 \text{ nm})/\text{Fe}_3\text{O}_4$  system increases by a factor of  $\sim 1.4$  compared to that at 300 K, while the magnetization of  $\text{Fe}_3\text{O}_4$  increases only by  $\sim 1.05$  in the same  $T$  range, as mentioned in Sec. III C.

Our results are distinct also from the recent XMCD results in the Pt(2 nm)/ $\text{Fe}_3\text{O}_4$  film reported by Collet *et al.* in Ref. 37, in which the XMCD signal was undetectably small at the temperatures above and below  $T_V$  (290 and 10 K). Here, their Pt film was formed with room-temperature sputtering, while our Pt films were fabricated with high-temperature sputtering ( $\sim 480^\circ\text{C}$ ). This difference in the fabrication process may affect the resultant XMCD signal.

Very recently, Vasili *et al.*<sup>38</sup> reported systematic XMCD results in Pt(4 nm)/ $\text{CoFe}_2\text{O}_4$  films, where the Pt deposition temperature was varied. They observed a large XMCD signal in a Pt/ $\text{CoFe}_2\text{O}_4$  sample when the Pt film is formed at a high temperature of  $400^\circ\text{C}$ , whose Pt ferromagnetic moment value was determined to be  $m_{\text{tot}} = 0.24 \mu_B$ .<sup>38</sup> This is in contrast to the absence of the XMCD signal in the other Pt/ $\text{CoFe}_2\text{O}_4$  sample, where the Pt film is formed at room temperature.<sup>38</sup> Through systematic XAS and XMCD measurements at the Fe and Co  $L_{3,2}$ -edges in both the total electron yield (TEY) and fluorescence yield (FY) modes and also STEM-EELS observations, they found that, in the high- $T$  grown Pt/ $\text{CoFe}_2\text{O}_4$  sample, the XAS and XMCD spectra for the (surface-sensitive) TEY mode contain metallic Fe and Co signals and also found that the Pt/ $\text{CoFe}_2\text{O}_4$  interface becomes less sharper than that deposited at room  $T$ . From these results, they concluded that, in the high- $T$  grown Pt/ $\text{CoFe}_2\text{O}_4$  sample, there are an interfacial Pt-(Co, Fe) alloying and/or a (Co, Fe)-interdiffusion into the Pt layer, which are negligible for the room- $T$  grown one.<sup>38</sup> The feature results in the large (negligibly small) XMCD for the high- $T$  (room- $T$ ) grown sample.

Based on the above arguments, the large XMCD signal and large Pt ferromagnetic moment observed in the present  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  systems prepared at a high temperature can be interpreted in terms of the possible heat-induced Fe interdiffusion into the Pt layer and Pt-Fe alloying (cannot be explained by the conventional interfacial magnetic proximity-induced Pt ferromagnetism). This scenario is also supported by our experimental facts, as shown below. (1) The Pt/ $\text{Fe}_3\text{O}_4$  interfaces are not atomically sharp and the interdiffusion is likely to be present (Sec. III A 2). (2) The Pt ferromagnetic moment  $m_{\text{tot}}$  increases more strongly than the  $T$  dependence of  $M$  of  $\text{Fe}_3\text{O}_4$  (i.e., the present  $m_{\text{tot}}$  does not correlate with the  $M$  intensity of  $\text{Fe}_3\text{O}_4$ , different from the previous reports) (Secs. III C and III E). (3) The  $m_{\text{tot}}$  value remains almost unchanged (decreases by only 10%) by increasing the Pt thickness from 2 to 5 nm, which does not agree with the proximity-induced Pt ferromagnetism scenario and is indeed different from the previous Pt thickness dependent XMCD results in Pt/Co bilayers, where the Pt films are deposited at room temperature<sup>48</sup> (Sec. III D). Furthermore, we confirmed that the XAS and XMCD results in the TEY mode for the Fe  $L_{3,2}$ -edges of our Pt( $\sim 5 \text{ nm}$ )/ $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2 - 3 \text{ nm})/\text{Fe}_3\text{O}_4$  reasonably agree with the results in the high- $T$  grown Pt/ $\text{CoFe}_2\text{O}_4$  reported by Vasili *et al.*,<sup>38</sup> indicating the presence of metallic Fe states in our Pt layer (see Sec. C in the supplementary material for details). The result

also supports our present scenario on the origin of the large induced Pt ferromagnetism in the  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  systems. Nevertheless, further work would be needed to obtain a complete physical picture of the present large Pt ferromagnetism.

#### IV. CONCLUSION

To summarize, by means of XMCD, we have investigated the induced Pt ferromagnetism in  $\text{Fe}_3\text{O}_4/\text{Pt}(t_{\text{Pt}} \sim 2 \text{ and } 5 \text{ nm})/\text{Fe}_3\text{O}_4$  epitaxial trilayer films at various temperatures, covering the metal-insulator transition temperature of  $\text{Fe}_3\text{O}_4$  ( $T_V \sim 114 \text{ K}$ ). The result shows the appearance of the large induced Pt ferromagnetic moment  $m_{\text{tot}}$  of  $0.39 \mu_B$  ( $0.36 \mu_B$ ) at 300 K and  $0.52 \mu_B$  at 12 K for the  $t_{\text{Pt}} = 2 \text{ nm}$  (5 nm) sample. The value does not follow the conventional scaling on  $m_{\text{tot}}$  vs volume magnetization  $M_{\text{FM}}$  of the magnetic layers. The appearance of the large XMCD (Pt ferromagnetism) in the present  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  systems prepared at a high temperature of  $480^\circ\text{C}$  is different from the absence of the measurable XMCD in  $\text{Pt}/\text{Fe}_3\text{O}_4$  in the recent report in Ref. 37, where the Pt film is formed at room temperature. Our results can be interpreted in terms of the possible heat-induced Fe interdiffusion into the Pt layer and Fe-Pt alloying due to its high-temperature deposition.

Recently, some of the present authors found measurable anomalous Nernst signals in  $\text{Fe}_3\text{O}_4/\text{Pt}/\text{Fe}_3\text{O}_4$  epitaxial trilayers in a wide temperature range even below  $T_V$  of  $\text{Fe}_3\text{O}_4$ . The result is attributed to the magnetized Pt due to the possible Fe interdiffusion into the Pt layer by the high-temperature Pt deposition, in a similar way to the present study.<sup>21</sup> We anticipate that our comprehensive temperature, magnetic field, and Pt thickness dependent XMCD results provide useful information to elucidate the origin of their observation.<sup>21</sup>

#### SUPPLEMENTARY MATERIAL

See the [supplementary material](#) for the details of XMCD sum-rule analysis and XAS and XMCD full spectra for the Pt  $L_{3,2}$ -edges of  $\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2 \text{ nm})/\text{Fe}_3\text{O}_4$  at  $T = 12 \text{ K}$  and for the Fe  $L_{3,2}$ -edges of  $\text{Pt}(\sim 5 \text{ nm})/\text{Fe}_3\text{O}_4/\text{Pt}(\sim 2 - 3 \text{ nm})/\text{Fe}_3\text{O}_4$  sample at room temperature.

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